



Exceptional service in the national interest

SANDIA NATIONAL LABORATORIES MICROSYSTEMS CAPABILITIES

DARPA ERI

Sr. Manager, Advanced Semiconductor Technologies **Rick McCormick**

August, 2020

SAND#:

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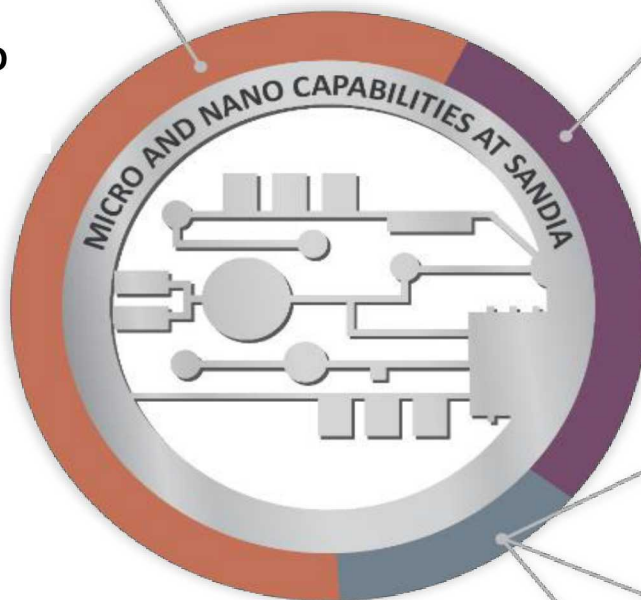
Sandia National Laboratories is a multimission laboratory managed and operated by National Technology and Engineering Solutions of Sandia, LLC, a wholly owned subsidiary of Honeywell International Inc., for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-NA0003525.

SANDIA'S MICROSYSTEM CAPABILITIES



MESA

**MICROSYSTEMS
ENGINEERING, SCIENCE, AND
APPLICATIONS**



CDC

**COUNTERFEIT
DETECTION CENTER**



CINT

**CENTER FOR INTEGRATED
NANOTECHNOLOGIES**



IBL

ION BEAM LABORATORY



RAD TEST FACILITIES

- HERMES III ACCELERATOR
- Z ACCELERATOR FACILITY
- ANNULAR CORE RESEARCH REACTOR (ACRR)



One of 3 DOE Nuclear Deterrence Labs (primarily “non-nuclear components”)

Missions: Nuclear Deterrence, Nonproliferation/Global Security, Energy & Homeland Security, and DoD and OGA support

Broad, unique capabilities & facilities:

Deep electronics & microsystems S&T capabilities: process technologies, materials science, reliability physics, extreme environments

Facilities: MESA fabs, Center for Integrated Nanotechnologies (CINT), Ion Beam Lab (IBL), Radiation Testing/Modeling, High Performance Computing

SANDIA PARTNERING AND TECHNOLOGY TRANSFER



Gov't Agencies & Labs



Large & Small Businesses



Universities



Many partners/projects for DARPA



MESA

MICROSYSTEMS, ENGINEERING, SCIENCE & APPLICATIONS

- Federally Funded Research & Development Center (FFRDC) with the broadest and deepest micro and nano expertise, providing what industry cannot, will not, or should not
- Only source for custom trusted strategically radiation hard (TSRH) microelectronics for the Department of Energy's (DOE) National Nuclear Security Administration (NNSA)
- Largest government owned microfabrication facility with two (Silicon and Compound) fabs

Research &
Development

Si μ Sys
(CMOS)

III-V μ Sys
(HBT)

MEMS

Photonics
(Si, III-V)

Production



Trusted
Design – Fabrication – Packaging
Heterogeneous Integration
Reliability & Failure Analysis
Radiation Effects Testing
Qualification – Product Acceptance

~300,000 parts across 44 products:

- 13 Si CMOS7 ASICs
- 8 III-V HBT SSICs
- 1 multi-kV GaN Diode
- 1 MEMS Sensor
- 2 Photonic Arrays
- 1 Optoelectronic Device
- 2 Focal Plane Arrays
- 16 RFICs



- 40 yrs. of Research & Product impact
- >300 Patents
- Tech. Transfer
- 45 R&D 100 Awards
- Seminal contributions to radiation hardened microelectronics, MEMS, & photonics

SANDIA'S MICROSYSTEM CAPABILITIES



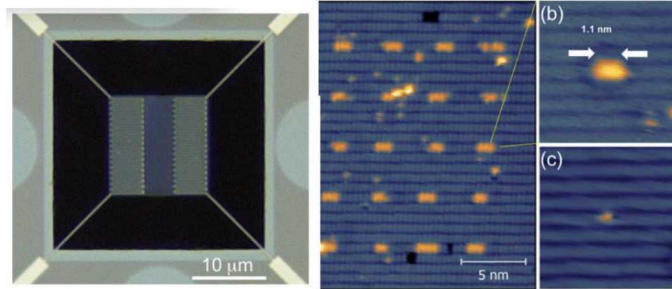
CINT CENTER FOR INTEGRATED NANO- TECHNOLOGY

DOE Nanoscale
Science Research
Center (User Facility)

- User-project proposal process
- 250+ projects accepted each year
- No-fee for pre-competitive research
- Full recovery for cost proprietary research
- 2 Facilities (SNL/LANL-total 130,000 gsf)
- 55 scientists/techs, 32+ postdocs/stdnts
- 800+ users engaged
- 300+ publications annually

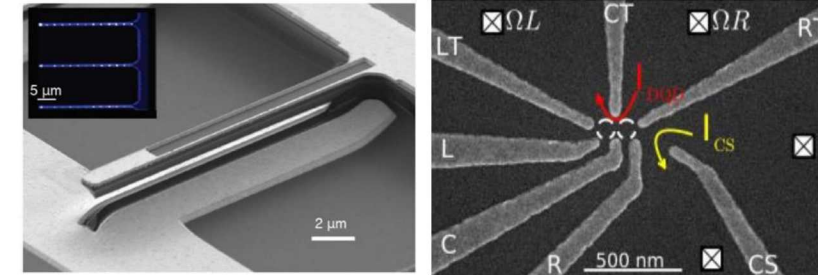
Forefront Lithography

- Atomic-Precision Lithography
- Focused ion implantation



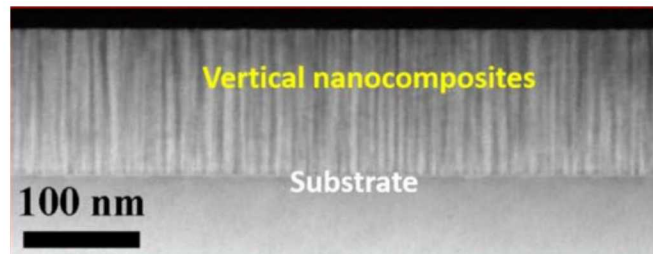
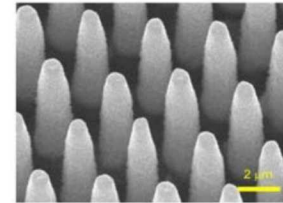
Quantum Science

- Quantum Transport
- Mean-field modeling for quantum materials



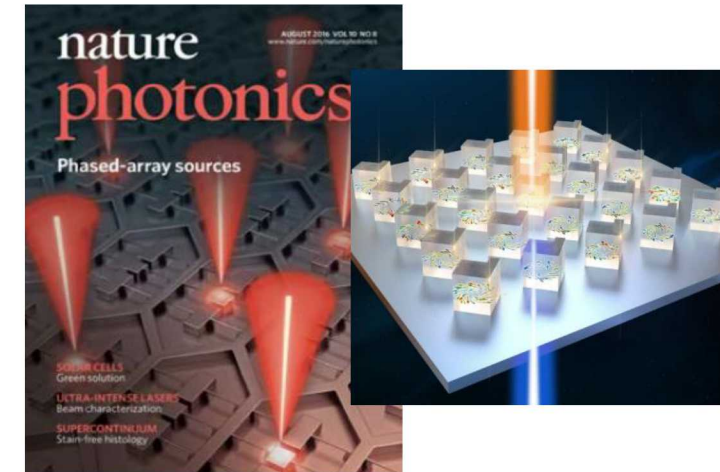
Materials synthesis

- Ultra-High Mobility MBE
- Complex Oxide PLD
- CVD Nanowire Growth



Nanophotonics

- Semiconductor metasurfaces
- Plasmonics, nanoparticles



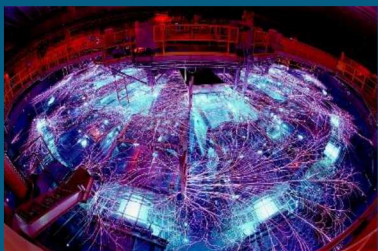
SANDIA'S MICROSYSTEM CAPABILITIES

6



IBL ION BEAM LABORATORY

- 6 Operational nano-implant systems
- Spot sizes from 0.5nm to mm's
- Energies from 5keV to 70MeV
- Single ion implantation
- <40nm targeting resolution possible
- 26 ion species in use, 40+ ions possible



RAD EFFECTS

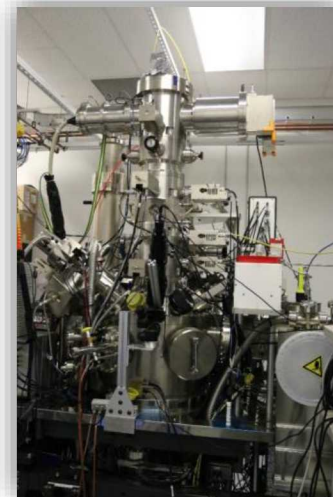
- Reactors, Accelerators, Z-machine
- Neutron, Gamma, X-ray, EMP
- Broad suite of RadFx Models/Codes

IBEC



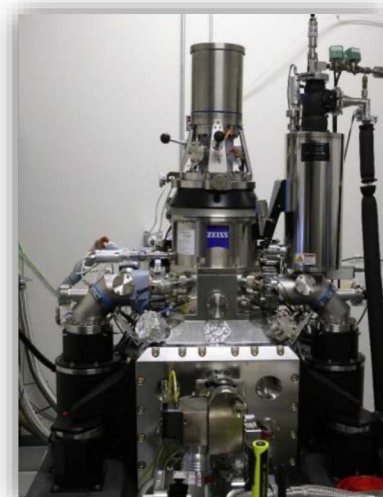
Ion Beam Induced Charging on
PIN Diode

NanoImplanter



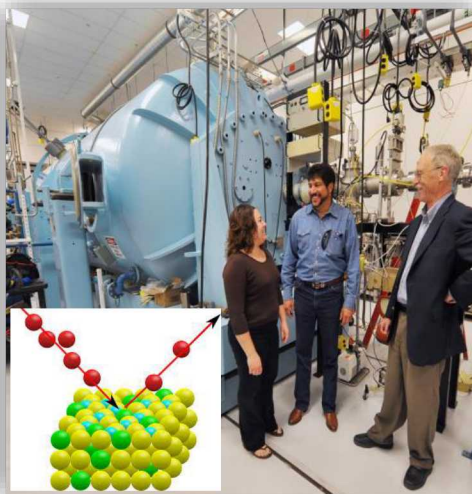
100 keV A&D FIB100NI

He microscope



100 keV Zeiss Orion Plus

Ion Beam Spectroscopy



HVE 6 MV Tandem

FIB-SEM NanoFab



35 keV Raith Velion

AC-STEMs



200 keV FEI Titan G2 8200



NEUROMORPHIC SCIENCE, PROCESSORS, & APPLICATIONS R&D



Basic Science: 2011-Today

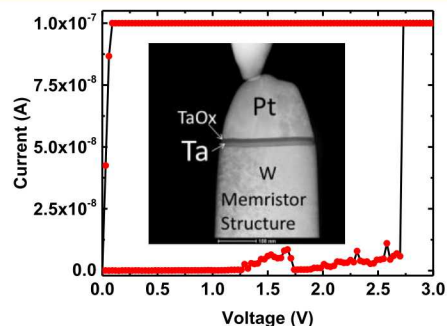
Memristors: HP Labs, Stan Williams
Matl Sci, Rad Fx, ReRAM NVM,
Neuro computing start
IBL nImplater, AC-STEM

Multiscale Integration:

Hardware Acceleration of Adaptive Neural Algorithms
(HAANA) Grand Challenge,
\$15M, 3 yrs, ~30 staff, 3 divisions at SNL

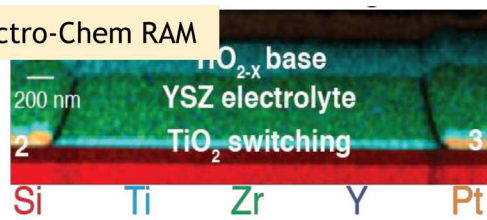
Application engagement:

Integration with Rad-hard CMOS,
National security and commercial
applications

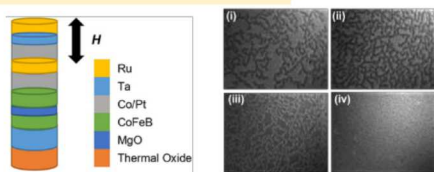


Electron Energy Loss Spectroscopy

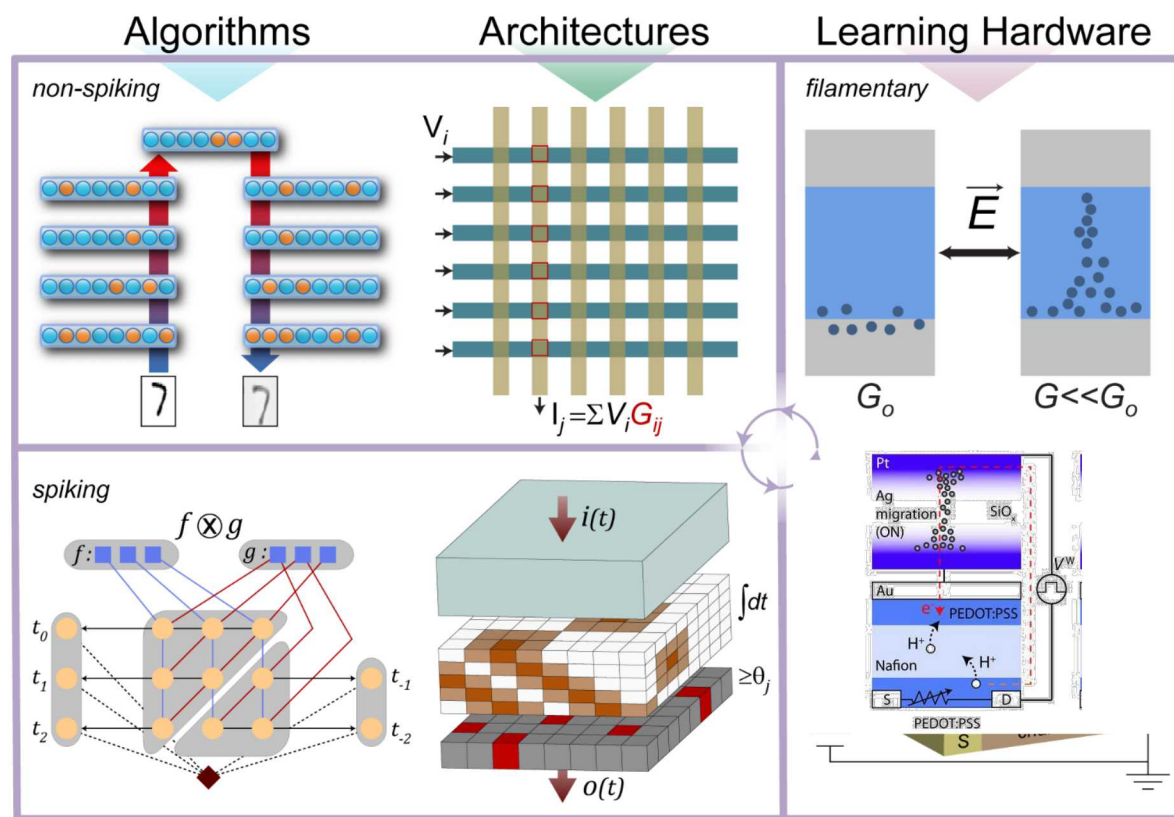
Electro-Chem RAM



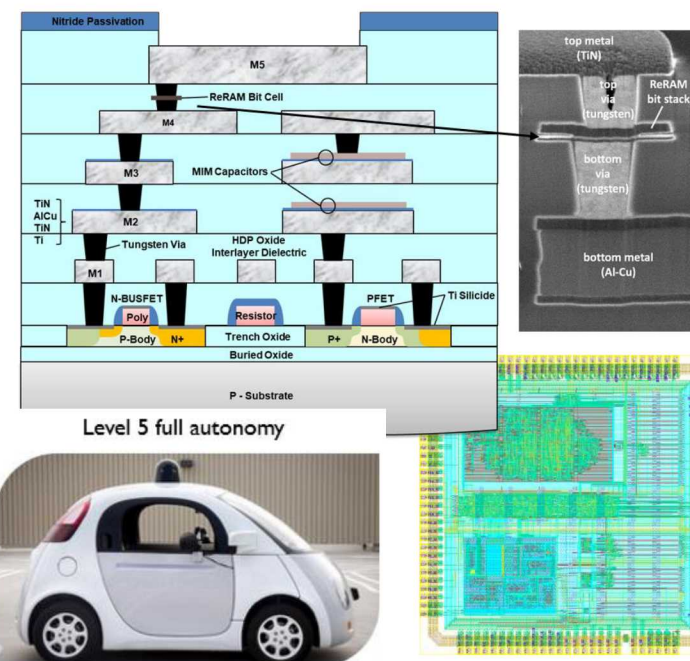
Rad Effects in STT pMTJs



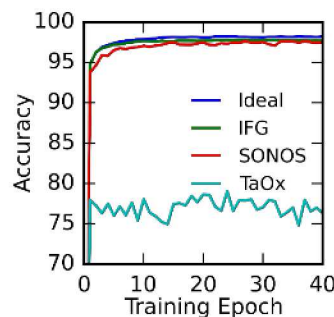
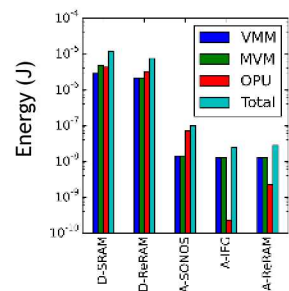
M. Alamdar et al., NSREC 2020



Fuller et al., Science 2019



MULTISCALE CoDESIGN FOR NEUROMORPHIC ACCELERATOR



Energy/Performance Model
Model performance and energy requirements

ROSS SIM

Sandia Cross-Sim:

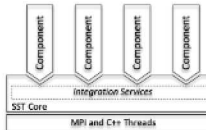
Translates device measurements and crossbar circuits to algorithm-level performance



Architecture

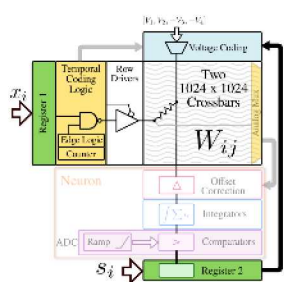
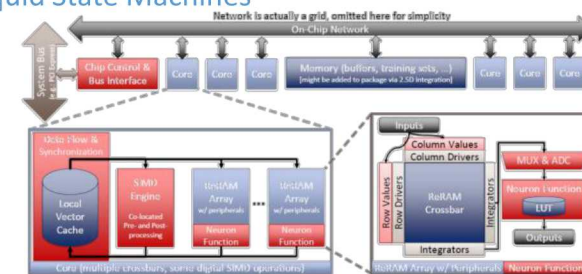
Algorithms

Architecture Simulation

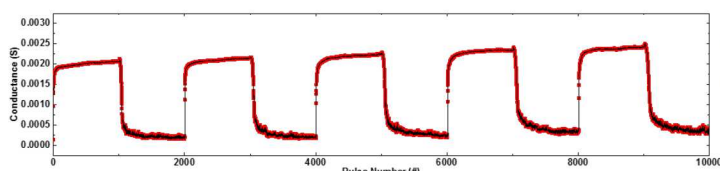


Target Algorithms

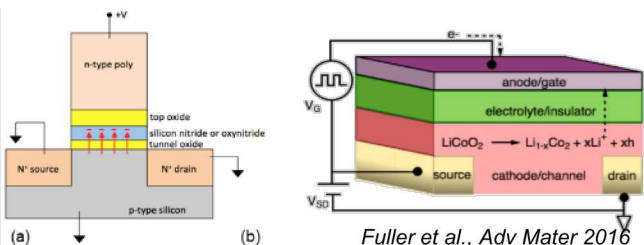
- Deep Learning
- Sparse Coding
- Liquid State Machines



Marinella, Agarwal et al JETCAS 2018

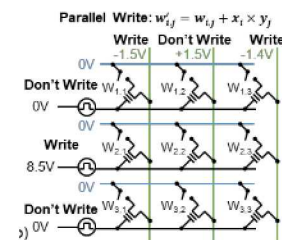
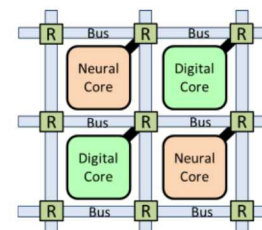


Analog characterization

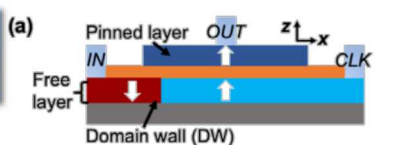
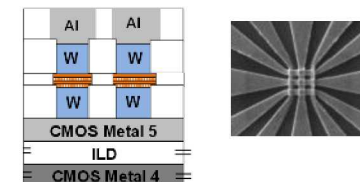
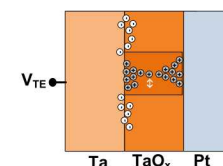


Fuller et al., Adv Mater 2016

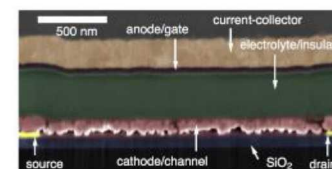
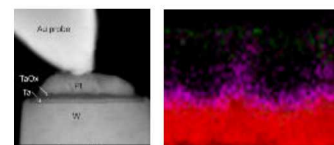
Circuits



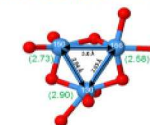
Drift-diffusion model of transport



In situ Characterization



Ab Initio Modeling



BACKUPS

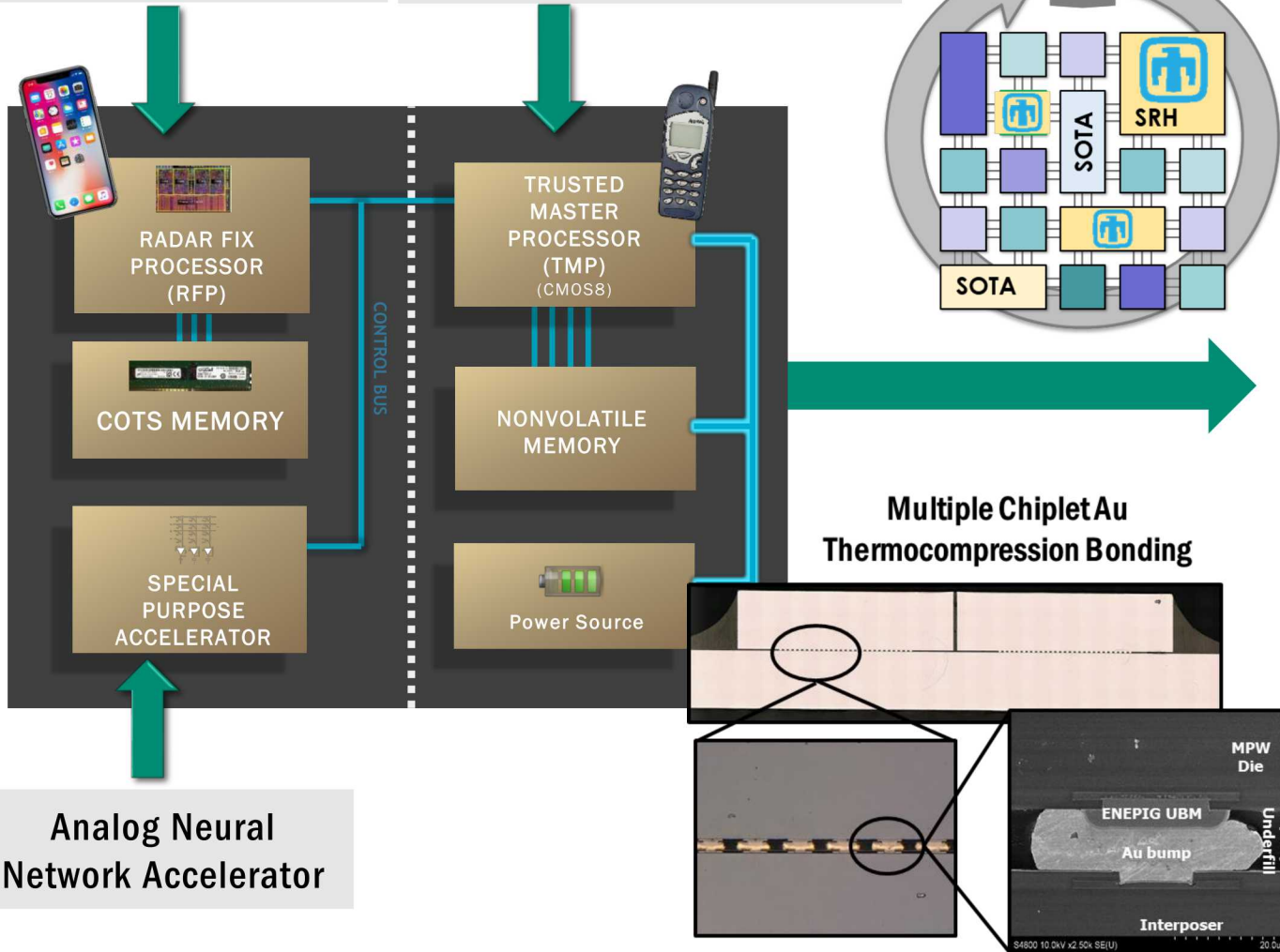


SEEEC (SECURE EFFICIENT EXTREME ENVIRONMENT COMPUTING) HIGH PERFORMANCE HETEROGENEOUS RAD HARD ARCHITECTURE

\$9M, 3 yrs, ~30 staff, 4 divisions at SNL

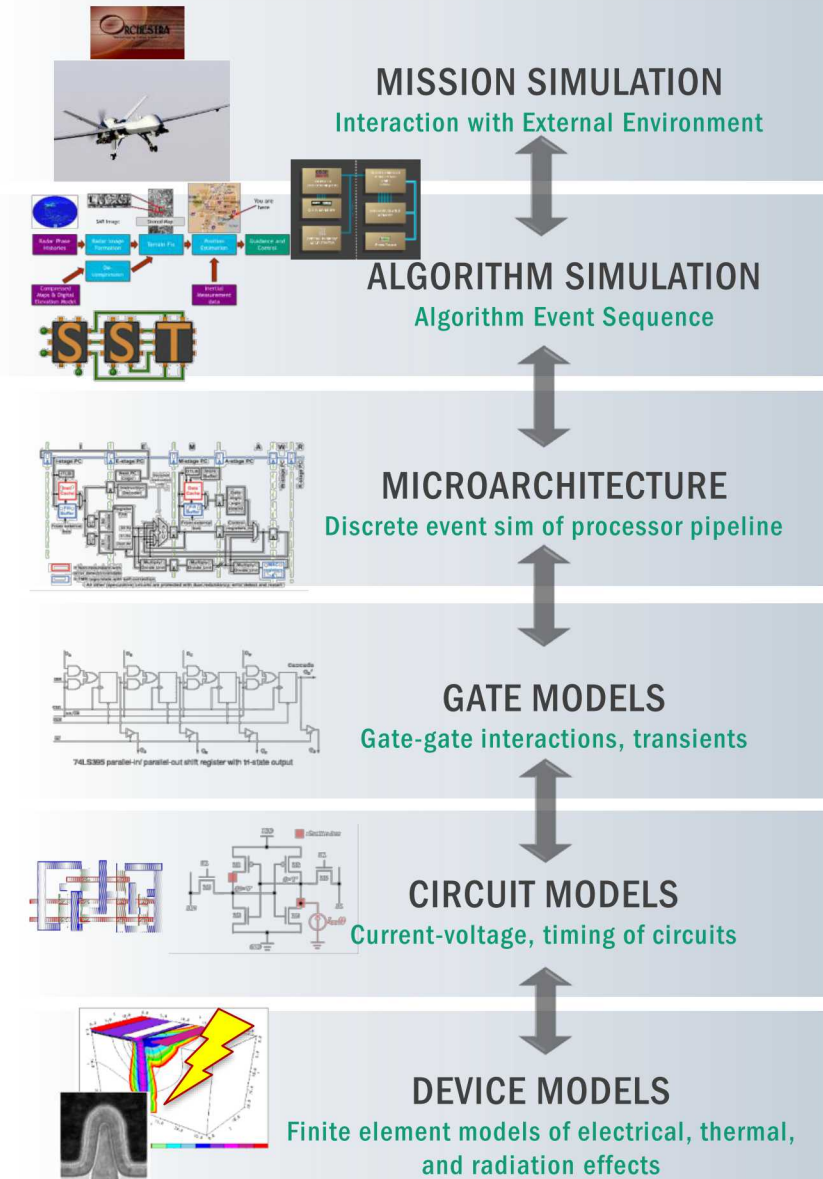
High Perf. Commercial Tech
Rad Hard by Design

Lower Perf. Gov. Fab
Trusted, Rad Hard by Process



Multiscale codesign & analysis framework

Multiscale Modeling Framework



Microsystem-Enabled Photovoltaics

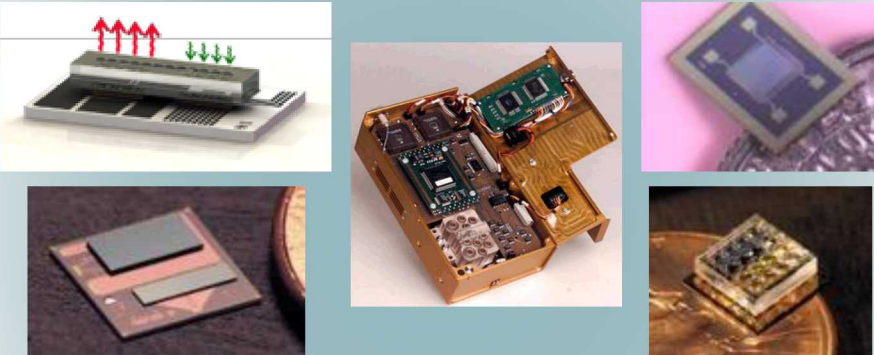


- wafer-level bonding for multi-junction solar cells
- InGaAsP/InP and InGaP/GaAs devices on silicon
- dielectric interfaces with III-V substrate removal
- integration with collection optics

Heterogeneous integration of Si and other materials

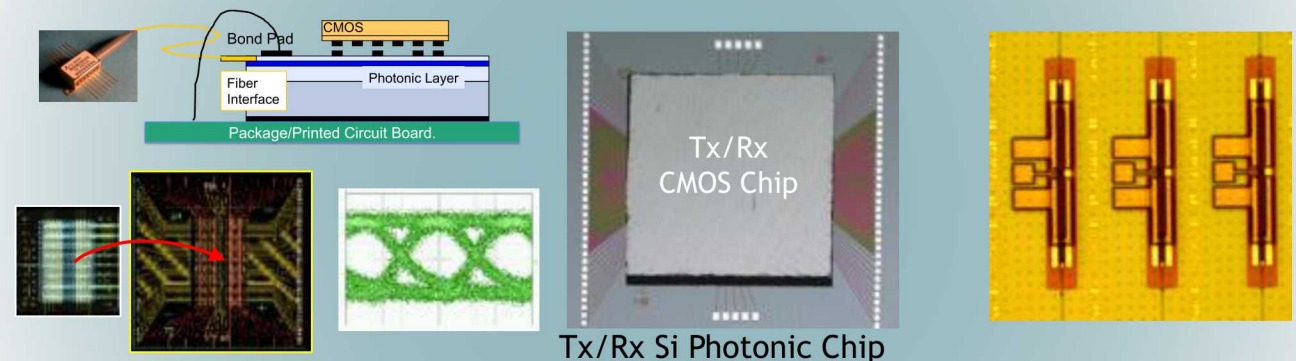
- Integration of LiNbO₃ and III-V technologies on silicon microelectronics and photonics
- Non-traditional materials such as Al₂O₃, epsilon-near-zero In₂O₃ and CdO, graphene
- Integration of CMOS with InGaAsP/InP, InGa/GaAs, silicon photonics, and other materials

Optical and MEMS-based Microsensors



- chemical and bio sensors using MEMS and SAW devices
- g-hard optical microsensors with in-house photonics
- hybrid device integration with custom micro-optics

CMOS / Silicon Photonics / III-V Integration



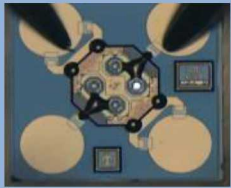
- silicon photonics on high-speed silicon ASIC
- independent optimization of electronics & photonics
- Gain and laser sources on silicon



Optoelectronics (OE)



GaN LED



Surface normal emitter/detectors

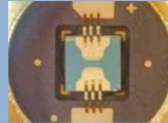
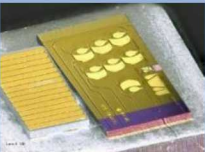
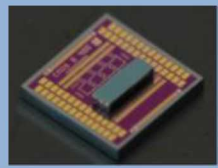


Photo-conductive Semiconductor Switch

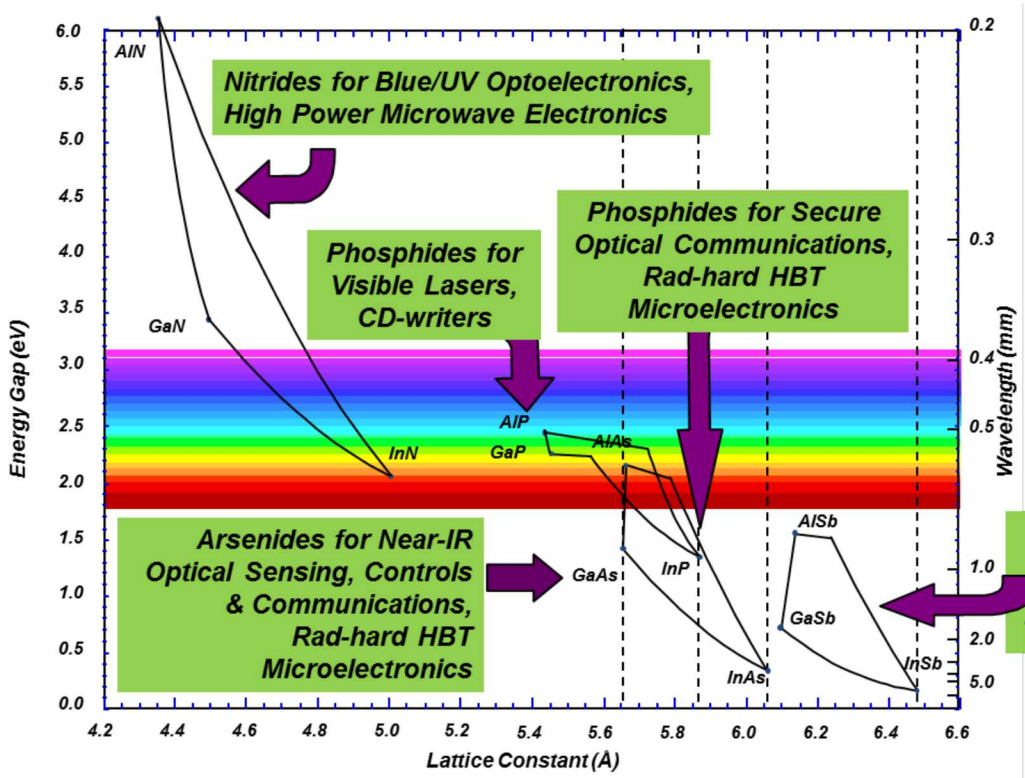


Photonic circuits

Hybrid Integration (HI)



Integrated OE and ME microsystems

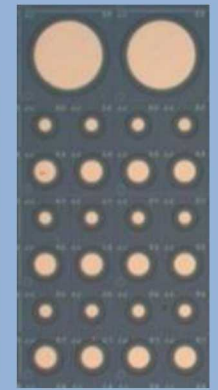
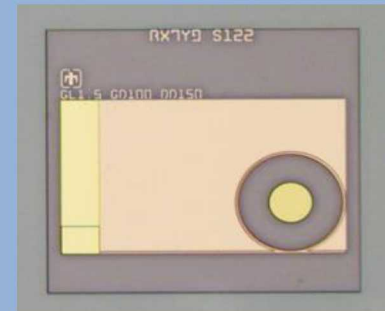


SNL has capability across full spectrum of III-V compounds

- Arsenides
- Phosphides
- Antimonides
- Nitrides

6 – MOCVD: As, P, Sb, N
6 – MBE: As, P, Sb
Production and R&D

GaN HV diodes

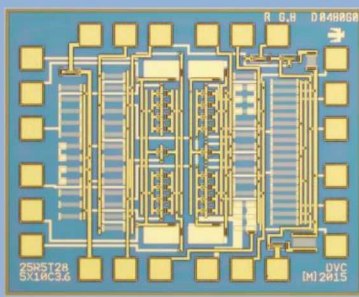


Focal Plane Arrays

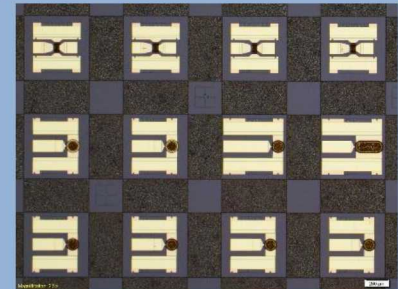


SNL FPA IR Image

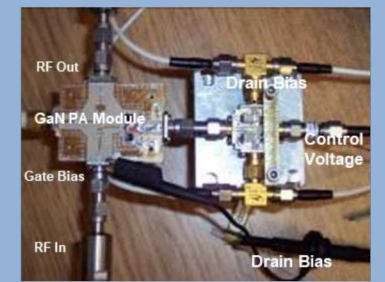
Microelectronics (ME)



HBT-based ICs



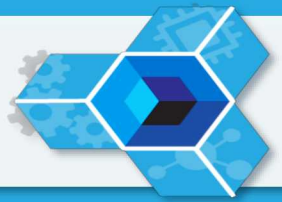
III-Nitride Power Transistors



III-N RF Power Amplifier

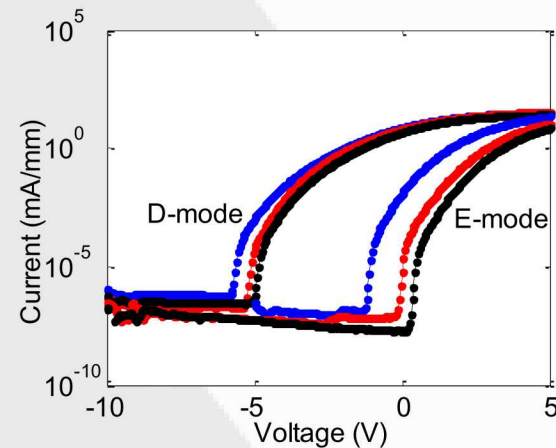
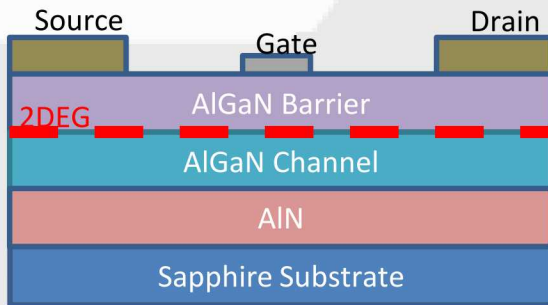
Digital Logic Gates for Extreme Environment Applications

Extreme environment hardening through intrinsic material properties

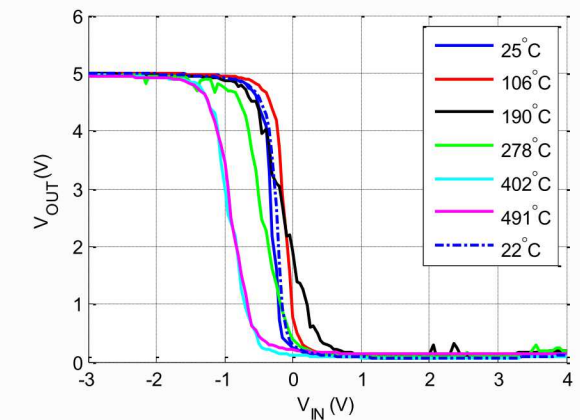
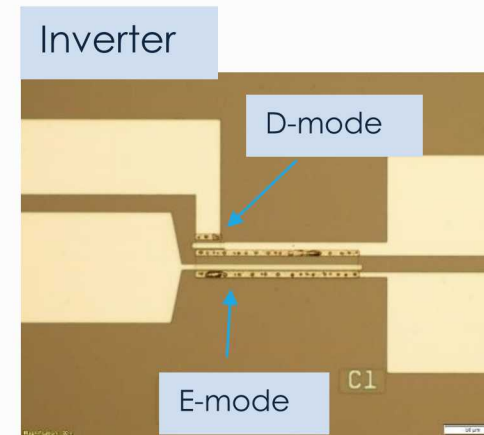


500 deg. C digital logic without extensive protection: Exploit ultra-wide bandgap AlGaN's superior electrical performance at elevated temperatures and high intrinsic material radiation tolerance

AlGaN High Electron Mobility Transistor (HEMT)



Adjacent **enhancement- and depletion-mode switches.**



Demonstration of $\text{Al}_{0.45}\text{Ga}_{0.55}\text{N}/\text{Al}_{0.3}\text{Ga}_{0.7}\text{N}$ Inverter **Operation from 25°C to 491°C.**

Material	E_g (eV)	E_{crit} ($\times 10^6$ V/cm)	v_{sat} ($\times 10^7$ cm/s)	Mobility ($\text{cm}^2/\text{V s}$)	Thermal Conductivity (W/m K)
AlN	6.0	15.4	1.3	426	319
$\text{Al}_x\text{Ga}_y\text{N}$	5.0-6.0	13.5-15.4	Interpolation	~ 150 -400	Interpolation
GaN	3.4	4.9	1.4	1000	253
b-Ga ₂ O ₃	4.9	10.3	1.1	180	11-27
Diamond	5.5	13.0	1.9-2.3	4500-7300	2290
SiC	3.3	2.5	2.0	1000	370

The ultra-wide band gap and high bond strength make AlGaN HEMTs promising for applications in extreme environments. The high critical electrical field may enable higher power density for switches.

Academic Partner: Georgia Tech: Sam Graham/Nick Hines

COMPOUND SEMICONDUCTOR ADVANCED R&D

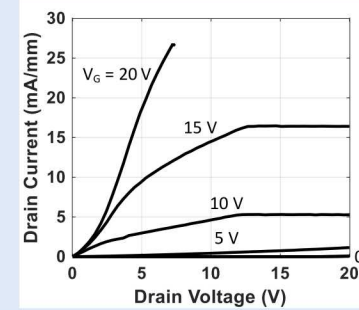


- Leveraging Expertise:
 - Materials Science
 - Materials Synthesis
 - Modeling/Simulation
 - Nanofabrication
 - HV Characterization
 - Reliability Science
 - Radiation Effects
 - Failure Analysis
- Striving to Improve:
 - Predictive Reliability
 - Qualification
 - Confidence
 - Manufacturing
 - Tolerances

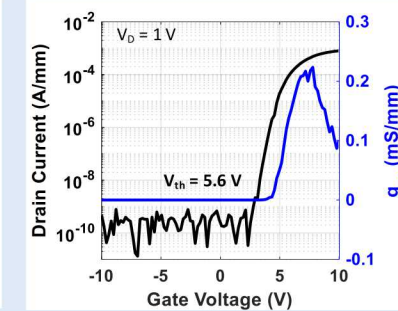


High-Voltage, Solid-State Switch (GaN MOSFET)

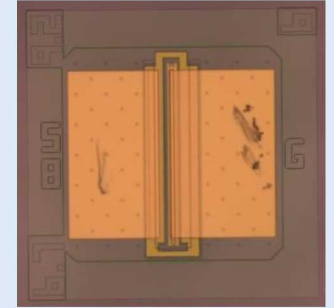
Low Current $I_D V_D$ Curves



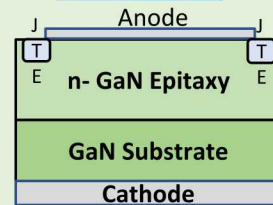
$I_D V_G$ – Transfer Characteristics



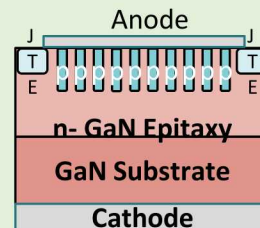
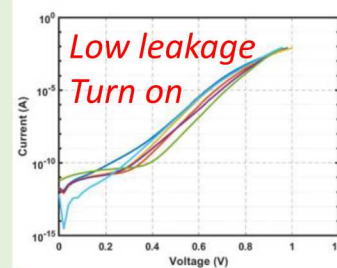
Optical Image



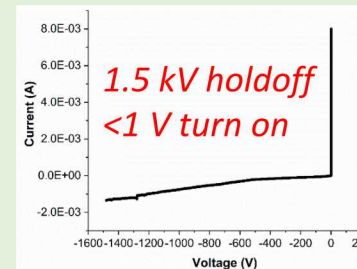
DOE-VTO GaN Power Diodes



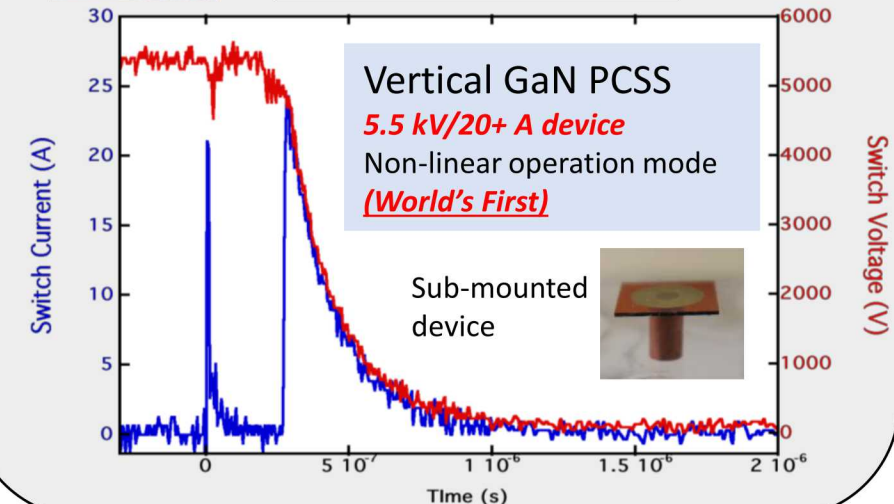
GaN Schottky Barrier Diode (SBD)



GaN Junction Barrier Schottky (JBS) Diode



ARPA-E BREAKERS DC Circuit Breaker



Sandia's National Security Photonic Center



MULTI-PROJECT WAFER OFFERINGS

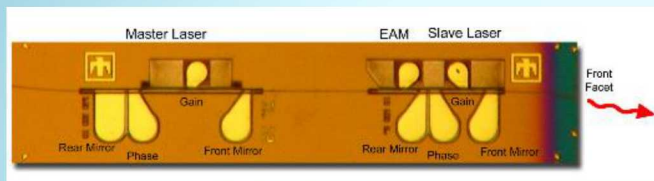


InP Photonics

- **3 tier offerings at 1550nm**
 - Tier 1: one regrowth
 - Tier 2: 2 regrowths (High P_{sat} Amplifier)
 - Tier 3: Full custom process



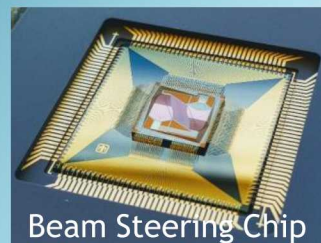
RF-Optical Channelizing Filter
1-20 GHz RF on C-Band Light



On-Chip Injection Locking
Enhanced Modulation > 50 GHz, C-Band

Silicon Photonics

- **MPW Device Library**
 - 20 Active, 22 Passive Components
 - Synopsis OptoDesigner
 - 200mm SOI Platform
 - Three Deliverables
 - Passive
 - Passive + Active
 - Passive + Active + Germanium



Beam Steering Chip

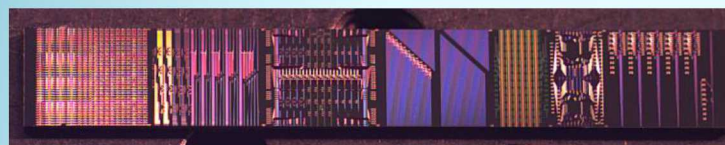
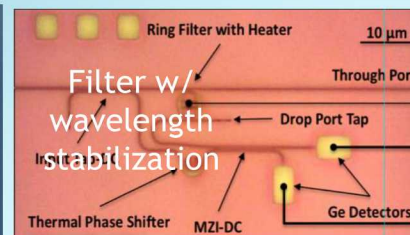
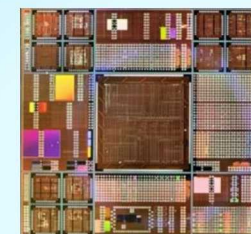
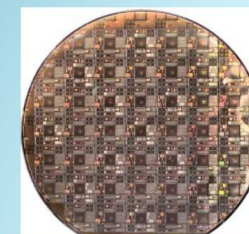


Image of MPW run, supporting Columbia, U of AZ, UC Berkeley, UCSD & Caltech

CMOS7

- **Multiple Engagement Models**
 - Full design & implementation by customer
 - Full design & implementation by Sandia
 - Anywhere in between
- **Non-Standard, custom processes**
 - AlN for resonators
 - Large-area graphene deposition
 - Deep trench capacitors
 - Prototype non-volatile memory
 - Thick metal
 - RF devices

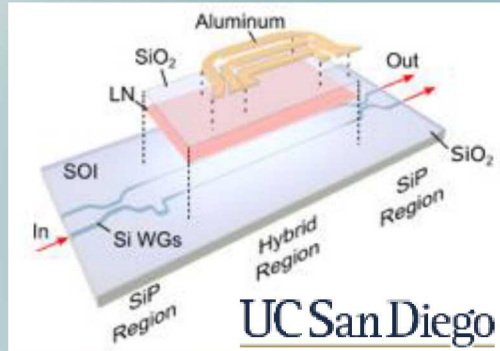


MPW & CMOS Design Contact:

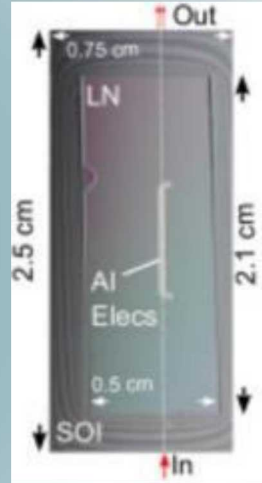
Ann Petersen, Manager
Advanced CMOS Products/Design
505-844-3160
annpete@sandia.gov

For more information:
photonics@sandia.gov

Optics Express 26 (18), 23728-23739, July 2018



Lithium Niobate on Silicon
100+GHz Bandwidth demonstrated

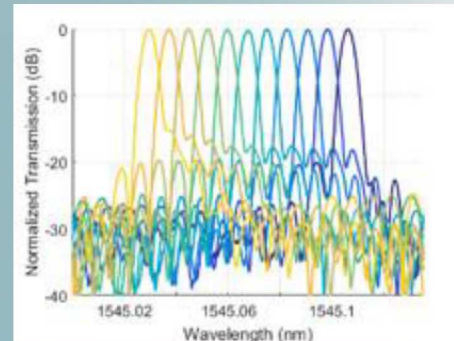


Photonic processing of RF signals provides significant reduction in SWAP-C for high frequency applications (>40 GHz)

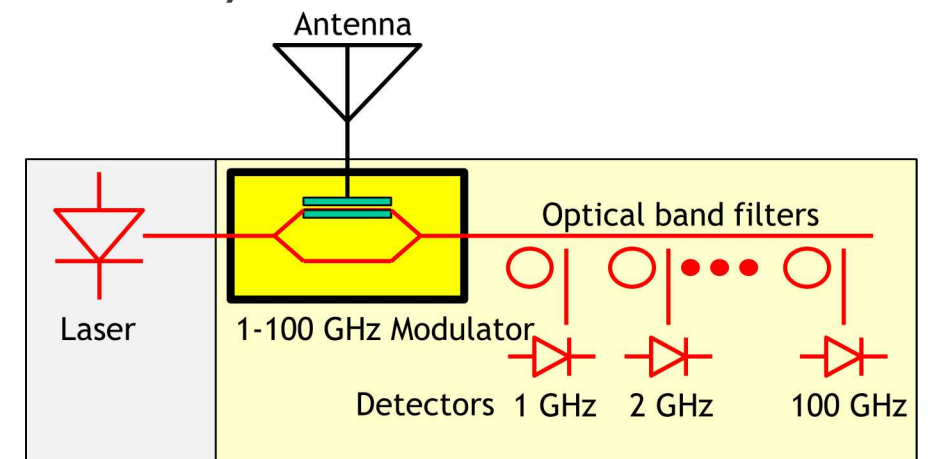
Applications in space and avionic platforms for electronic warfare and situational awareness

- Frequency up/down-conversion
- Antenna remoting
- RF over fiber
- Wide-band channelization
- Low loss RF delay lines

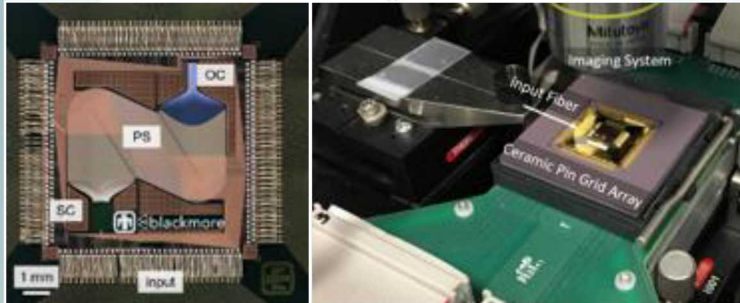
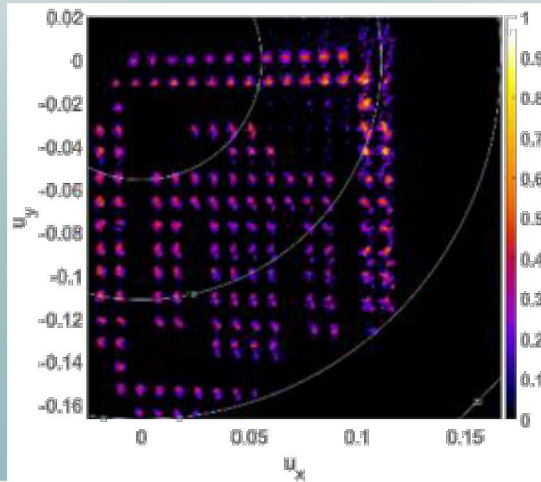
Optics Express 25 (6), 6320-6334, Mar. 2017



1st Demo of 1GHz RF Channelization in a Si Photonics Array Waveguide Grating



Example integrated wide-band channelizer



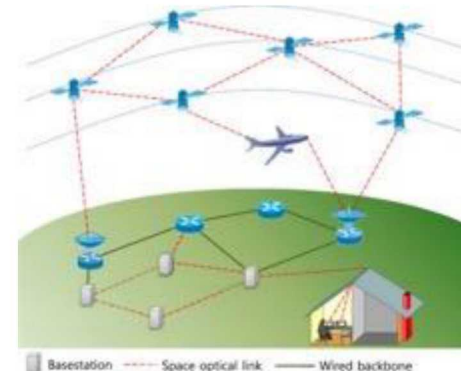
Phase Optimization of Si Photonics
2D Electro-optic Phased Array
(CLEO 2019 JTh2A.39)

2D Silicon Photonic Optical Beam Scanner

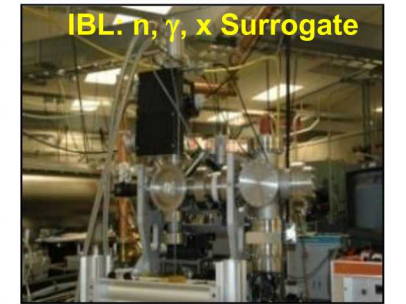
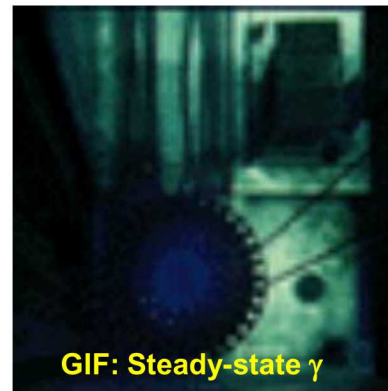
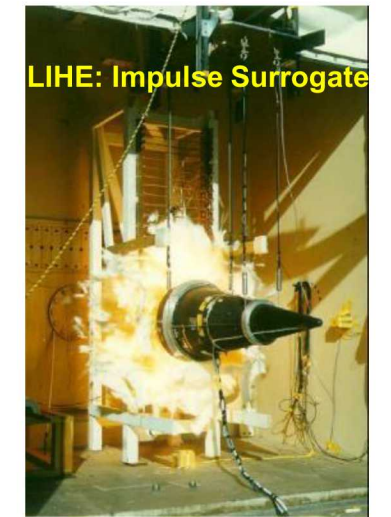
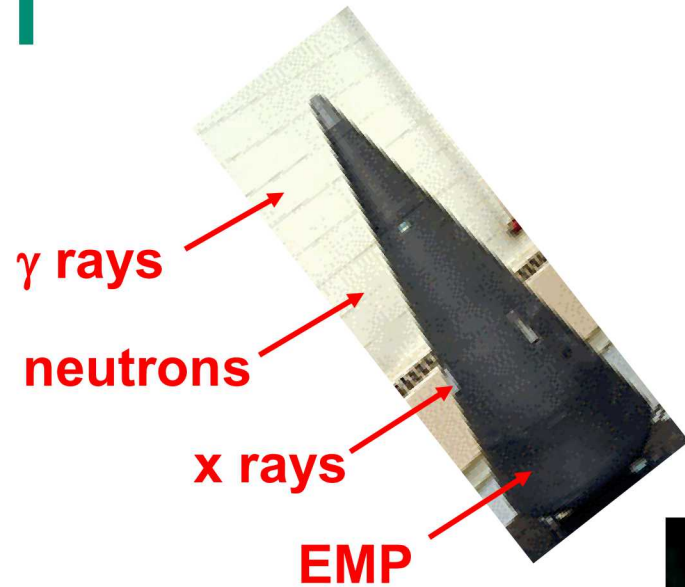
- Electronic (low-power EO phase shifter) and wavelength steering
- field of view: $24^\circ \times 10^\circ$; divergence angle: $0.3^\circ \times 0.3^\circ$
- 256 independent channels with 3- μm pitch
- Area: 750 μm x 750 μm with high fill factor

Applications

- Imaging and sensing
- Free-space communication



SANDIA RADIATION TEST FACILITIES



LIGHTNING: 1.6 MV, 200 kA

